

Accepted Manuscript

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PII: S1935-861X(17)31026-4

DOI: [10.1016/j.brs.2017.12.010](https://doi.org/10.1016/j.brs.2017.12.010)

Reference: BRS 1168

To appear in: *Brain Stimulation*

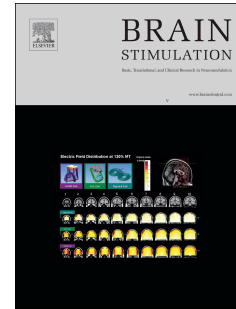
Received Date: 15 July 2017

Revised Date: 21 December 2017

Accepted Date: 27 December 2017

Please cite this article as: Kerwin LJ, Keller CJ, Wu W, Narayan M, Etkin A, Test-retest reliability of transcranial magnetic stimulation EEG evoked potentials, *Brain Stimulation* (2018), doi: 10.1016/j.brs.2017.12.010.

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Test-Retest Reliability of Transcranial Magnetic Stimulation EEG Evoked Potentials

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Running title: Test-Retest Reliability of TEPs

To be submitted:

Number of pages: 24

Number of figures: 6

Number of tables: 2

Abstract word count: 249

Intro word count: 761 w/citations

Discussion word count: 1042 w/citations

Intro-to-Discussion word count: 4342 w/ citations

Running title: Test-Retest Reliability of TEPs

Keywords: Transcranial magnetic stimulation (TMS), electroencephalogram (EEG), evoked potentials, reliability, plasticity

Funding: This work was funded by Big Idea in Neuroscience research funds from the Stanford Neurosciences Institute. LJK was funded by a Alpha Omega Alpha Carolyn L. Kuckein Student Research Fellowship.

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